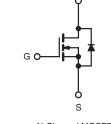


Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	100				
R _{DS(on)} (Ω)	$V_{GS} = 5.0 V$	0.16			
Q _g (Max.) (nC)	28				
Q _{gs} (nC)	3.8				
Q _{gd} (nC)	14				
Configuration	Single				





N-Channel MOSFET

FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Logic-Level Gate Drive
- $R_{DS(on)}$ Specified at $V_{GS} = 4 V$ and 5 V
- 175 °C Operating Temperature
- Fast Switching
- · Ease of Paralleling
- Lead (Pb)-free Available

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost effectiveness.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 W. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.

ORDERING INFORMATION	
Package	TO-220
Lead (Pb)-free	IRL530PbF
	SiHL530-E3
SnPb	IRL530
	SiHL530

ABSOLUTE MAXIMUM RATINGS $T_C = 25 \degree C$, unless otherwise noted						
PARAMETER	SYMBOL	LIMIT	UNIT			
Gate-Source Voltage		V _{GS}	± 10	V		
Continuous Drain Current	$V_{GS} \text{ at } 5.0 \text{ V} \frac{T_{C} = 25 \text{ °C}}{T_{C} = 100 \text{ °C}}$	- I _D	15			
	$T_{\rm C} = 100 ^{\circ}{\rm C}$		11	А		
Pulsed Drain Current ^a	I _{DM}	60				
Linear Derating Factor			0.59	W/°C		
Single Pulse Avalanche Energy ^b		E _{AS}	290	mJ		
Repetitive Avalanche Current ^a		I _{AR}	15	A		
Repetitive Avalanche Energy ^a		E _{AR}	8.8	mJ		
Maximum Power Dissipation	T _C = 25 °C	PD	88	W		
Peak Diode Recovery dV/dt ^c		dV/dt	5.5	V/ns		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 175	°C		
Soldering Recommendations (Peak Temperature)	for 10 s		300 ^d	C		
Mounting Torque	6-32 or M3 screw		10	lbf ⋅ in		
	0-32 OF WIS SCIEW		1.1	N ⋅ m		

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. $V_{DD} = 25 \text{ V}$, starting $T_J = 25 \text{ °C}$, L = 1.9 mH, $R_G = 25 \Omega I_{AS} = 15 \text{ A}$ (see fig. 12).

c. $I_{SD} \leq 15$ A, dl/dt ≤ 140 A/µs, $V_{DD} \leq V_{DS}$, $T_J \leq 175$ °C.

d. 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RA	TINGS							
PARAMETER	SYMBOL	TYP.		MAX.		UNIT		
Maximum Junction-to-Ambient	R _{thJA}	-		62				
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.50 -			°C/W			
Maximum Junction-to-Case (Drain)	R _{thJC}	- 1.7						
SPECIFICATIONS $T_J = 25 \ ^{\circ}C$,	unless other	wise noted						
PARAMETER	SYMBOL	TEST	CONDIT	IONS	MIN.	TYP.	MAX.	UNIT
Static					•	•		
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0	V, I _D = 2	250 μA	100	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference to	o 25 °C,	I _D = 1 mA	-	0.14	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{C}$	_{3S} , I _D = 2	250 μΑ	1.0	-	2.0	V
Gate-Source Leakage	I _{GSS}	Vo	$V_{GS} = \pm 10$		-	-	± 100	nA
		V _{DS} = 100 V, V _{GS} = 0 V		-	-	25		
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 80 V, V ₀	_{GS} = 0 V,	T _J = 150 °C	-	-	250	μA
	-	V _{GS} = 5.0 V	l _l	_D = 9.0 A ^b	-	-	0.16	-
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 4.0 V	I,	_D = 7.5 A ^b	-	-	0.22	Ω
Forward Transconductance	g fs	V _{DS} = 50 V, I _D = 9.0 A ^b		6.4	-	-	S	
Dynamic		.						
Input Capacitance	C _{iss}	V	0 V		-	930	-	
Output Capacitance	C _{oss}	VD	$V_{GS} = 0 V,$ $V_{DS} = 25 V,$ f = 1.0 MHz, see fig. 5		-	250	-	pF
Reverse Transfer Capacitance	C _{rss}	f = 1.0 N			-	57	-	
Total Gate Charge	Qg			5 A, V _{DS} = 80 V, a fig. 6 and 13 ^b	-	-	28	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 5.0 V			-	-	3.8	
Gate-Drain Charge	Q _{gd}	1	000		-	-	14	
Turn-On Delay Time	t _{d(on)}				-	4.7	-	-
Rise Time	t _r	- 	0 V I	15 Δ	-	100	-	
Turn-Off Delay Time	t _{d(off)}	V_{DD} = 50 V, I_D = 15 A, R_G = 12 Ω , R_D = 32 Ω , see fig. 10 ^b		-	22	-	ns	
Fall Time	t _f	-			-	48	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	nH	
Internal Source Inductance	L _S			-	7.5	-		
Drain-Source Body Diode Characteristic	s							
Continuous Source-Drain Diode Current	١ _S	showing the	MOSFET symbol showing the		-	-	15	А
Pulsed Diode Forward Current ^a	I _{SM}	p - n junction diode		-	-	60		
Body Diode Voltage	V_{SD}	T _J = 25 °C, I _S	; = 15 A,	$V_{GS} = 0 V^{b}$	-	-	2.5	V
Body Diode Reverse Recovery Time	t _{rr}	$T_{J} = 25 \text{ °C}, I_{F} = 15 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}^{b}$		-	150	200	ns	
Body Diode Reverse Recovery Charge	Q _{rr}			-	0.93	1.4	μC	
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)					L _D)	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width $\leq 300~\mu s;$ duty cycle ≤ 2 %.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

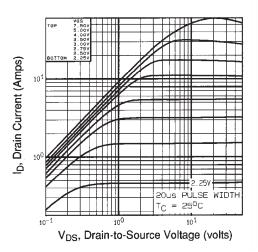


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

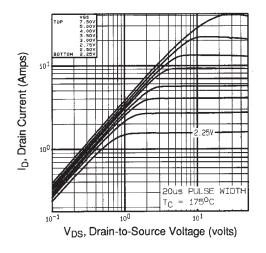


Fig. 2 - Typical Output Characteristics, $T_C = 175$ °C

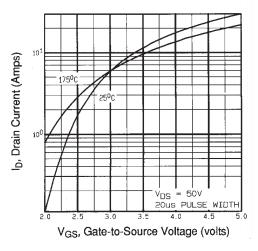


Fig. 3 - Typical Transfer Characteristics

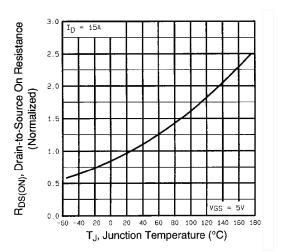


Fig. 4 - Normalized On-Resistance vs. Temperature



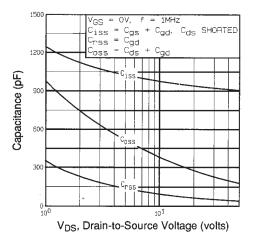


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

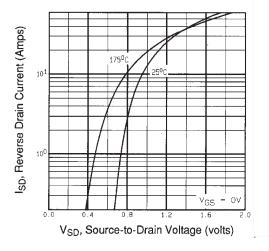


Fig. 7 - Typical Source-Drain Diode Forward Voltage

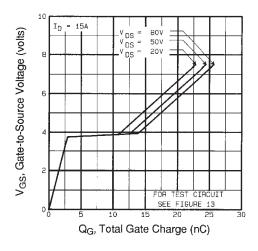


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

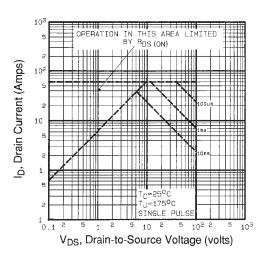


Fig. 8 - Maximum Safe Operating Area



IRL530, SiHL530

Vishay Siliconix

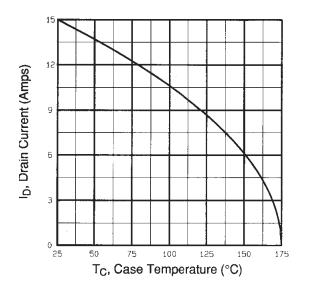


Fig. 9 - Maximum Drain Current vs. Case Temperature

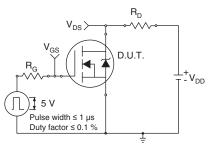


Fig. 10a - Switching Time Test Circuit

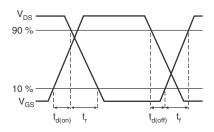


Fig. 10b - Switching Time Waveforms

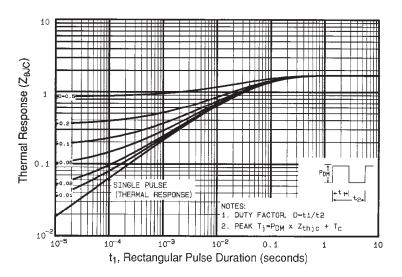


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

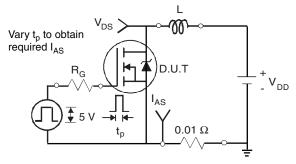


Fig. 12a - Unclamped Inductive Test Circuit

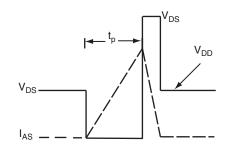


Fig. 12b - Unclamped Inductive Waveforms

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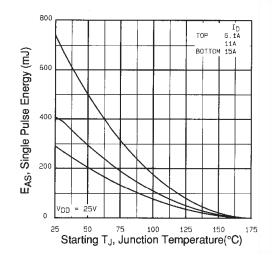


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

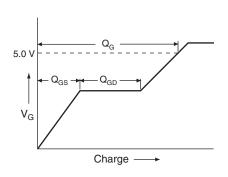
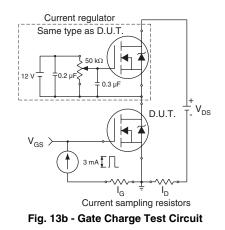
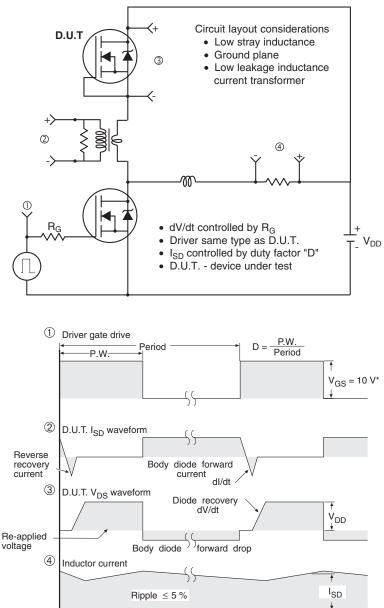


Fig. 13a - Basic Gate Charge Waveform









Peak Diode Recovery dV/dt Test Circuit

* $V_{GS} = 5$ V for logic level devices

Fig. 14 - For N-Channel

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